

ATOMIC FORCE MICROSCOPY (AFM)

MANUFACTURER : Digital Instruments

MODEL : Dimensions 3100

Samples

- Sample size: maximum 101 mm (4")
- Thickness: maximum 12.7 mm (0.5")
- Open geometry

Analysis

- Modes: Contact mode, Tapping mode, Lateral Force Microscopy (LFM), Magnetic Force Microscopy (MFM), Scanning Tunnel Microscopy (STM)
- Topographical measurements: quantitative
- Measurement of viscoelastic properties: qualitative
- Mapping possible
- Lateral resolution: 2 nm

Applications

- Measurements of topography in ambient or liquid environments
- Measurements of mechanical properties
- Measurement of friction
- Measurement of roughness
- Measurement of magnetic field gradients
- Measurement of electrical fields gradients
- Measurement of tip/surface interaction force